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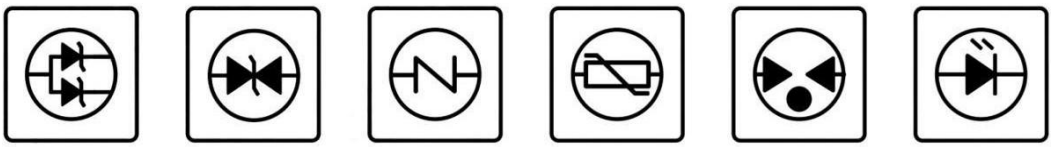


AON6226-MS

Product specification

Description

The AON6226-MS use advanced SGT MOSFET technology to provide low RDS(ON), low gate charge, fast switching and excellent avalanche characteristics.
This device is specially designed to get better ruggedness and suitable.

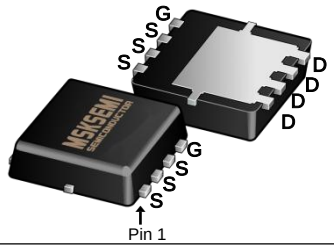
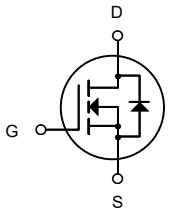
Features

- V_{DS} = 100V I_D= 75A
- $R_{DS(ON)}$ < 9.2mΩ V_{GS}= 10V

Application

- Consumer electronic power supply Motor control
- Synchronous-rectification Isolated DC
- Synchronous-rectification applications

Reference News

DFN5X6-8L	N-Channel MOSFET	Marking
		

Absolute Maximum Ratings at T_j=25℃ unless otherwise noted

Parameter	Symbol	Value	Unit
Drain source voltage	VDS	100	V
Gate source voltage	VGS	±20	V
Continuous drain current[1)]	ID	75	A
Pulsed drain current[2)]	ID, pulse	300	A
Power dissipation[3)]	P_D	97	W
Single pulsed avalanche energy[5)]	EAS	90	mJ
Operation and storage temperature	Tstg , Tj	-55 to 150	℃
Thermal rseistance, junction-case	RθJC	1.3	°C/W

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Electrical Characteristics (T_J=25℃ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Units
Off Characteristic						
$V_{(BR)DSS}$	Drain-Source Breakdown Voltage	V_{GS}=0V, I_D=250μA	100	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS}=100V, V_{GS}=0V,	-	-	1.0	μA
I_{GSS}	Gate to Body Leakage Current	V_{DS}=0V, V_{GS}= ±20V	-	-	±100	nA
On Characteristics						
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS}=V_{GS}, I_D=250μA	1.0	1.6	2.5	V
$R_{DS(on)}$	Static Drain-Source on-Resistance note3	V_{GS}=10V, I_D=20A	-	7.3	9.2	mΩ
		V_{GS}=4.5V, I_D=8A	-	9	13.5	mΩ
Dynamic Characteristics						
C_{iss}	Input Capacitance	V_{DS}=50V, V_{GS}=0V, f=1.0MHz	-	2046	-	pF
C_{oss}	Output Capacitance		-	865	-	pF
C_{rss}	Reverse Transfer Capacitance		-	25	-	pF
Q_g	Total Gate Charge	V_{DS}=50V, I_D=30A, V_{GS}=10V	-	39.4	-	nC
Q_{gs}	Gate-Source Charge		-	5.2	-	nC
Q_{gd}	Gate-Drain(“Miller”) Charge		-	9.8	-	nC
Switching Characteristics						
$t_{d(on)}$	Turn-on Delay Time	V_{DD}=50V, I_D=25A, R_G=6Ω, V_{GS}=10V	-	20	-	ns
t_r	Turn-on Rise Time		-	5.2	-	ns
$t_{d(off)}$	Turn-off Delay Time		-	49	-	ns
t_f	Turn-off Fall Time		-	12	-	ns
Drain-Source Diode Characteristics and Maximum Ratings						
I_S	Maximum Continuous Drain to Source Diode Forward Current		-	-	75	A
I_{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	300	A
V_{SD}	Drain to Source Diode Forward Voltage	V_{GS}=0V, I_S=30A	-	-	1	V
t_{rr}	Body Diode Reverse Recovery Time	T_J=25℃, I_F=12A,dI/dt=100A/μs	-	49	-	ns
Q_{rr}	Body Diode Reverse Recovery Charge		-	85	-	nC

Notes:

1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
2. EAS condition: T_J=25℃, V_{DD}=50V, V_G=10V, R_G=25Ω, L=0.5mH, I_{AS}=19A
3. Pulse Test: Pulse Width≤300μs, Duty Cycle≤0.5%

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Typical Performance Characteristics

Figure1: Output Characteristics

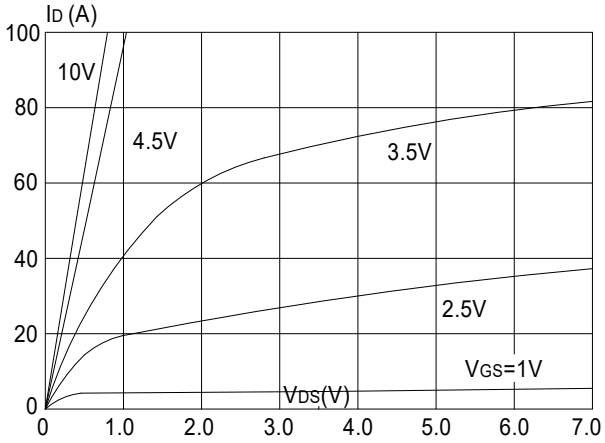

Figure 2: Typical Transfer Characteristics

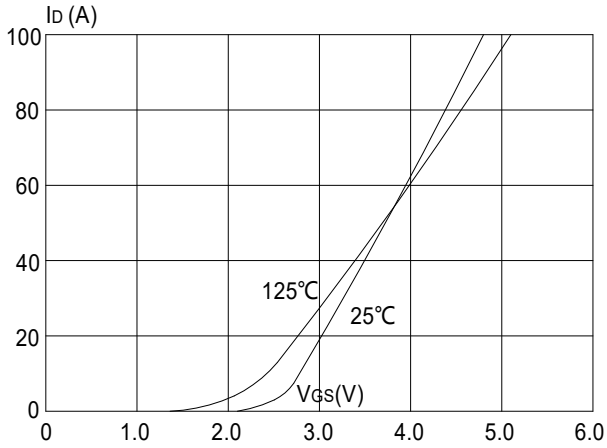

Figure 3: On-resistance vs. Drain Current

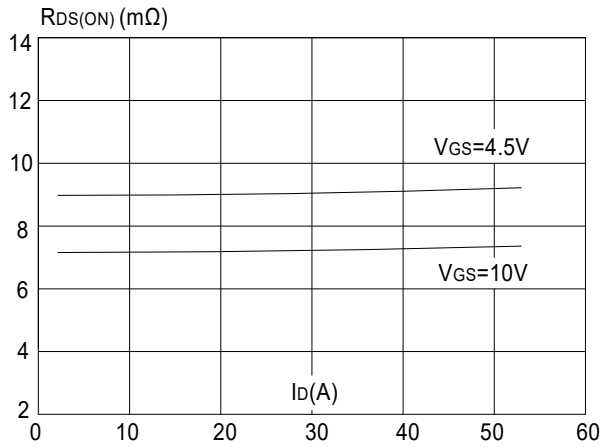

Figure 4: Body Diode Characteristics

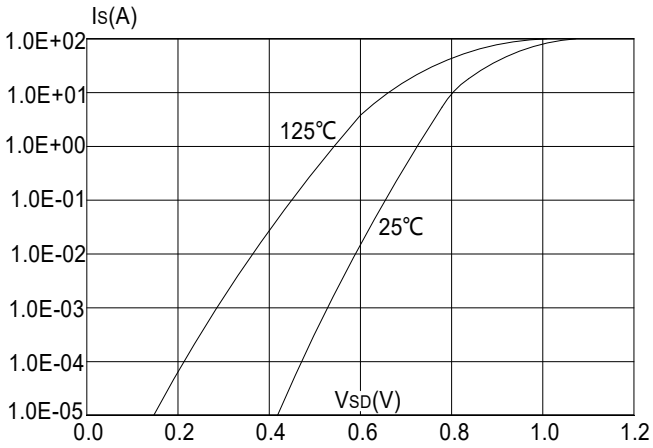

Figure 5: Gate Charge Characteristics

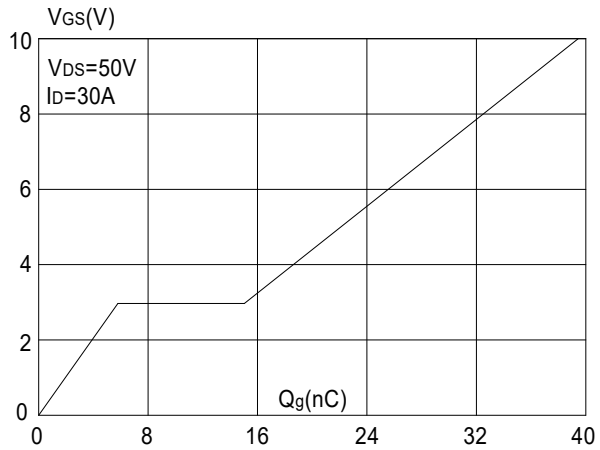

Figure 6: Capacitance Characteristics

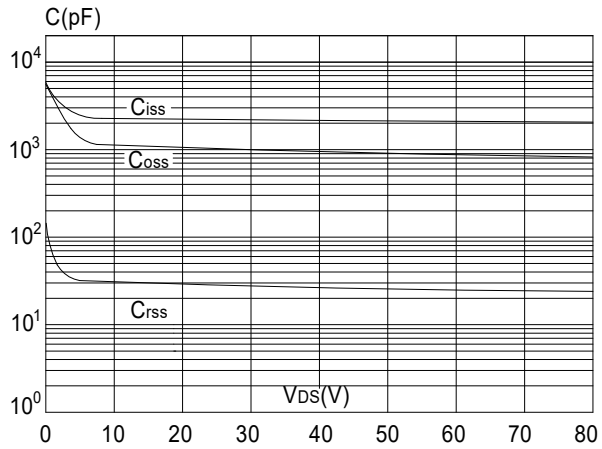

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Figure 7: Normalized Breakdown Voltage vs. Junction Temperature

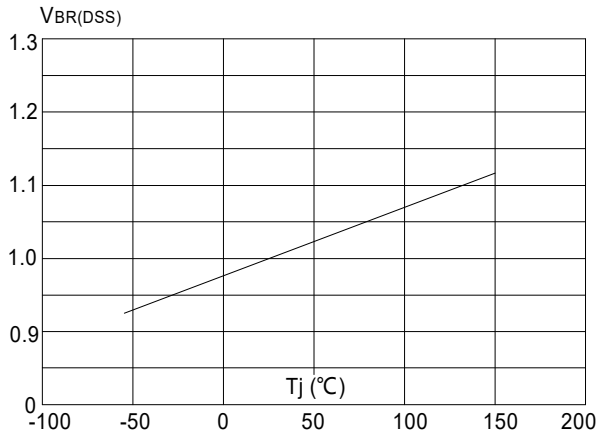


Figure 8: Normalized on Resistance vs. Junction Temperature

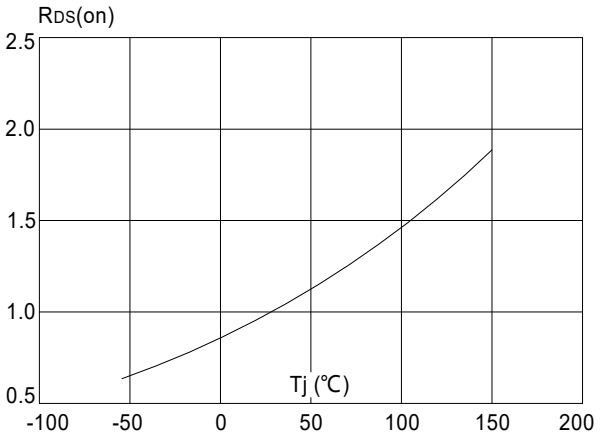


Figure 9: Maximum Safe Operating Area

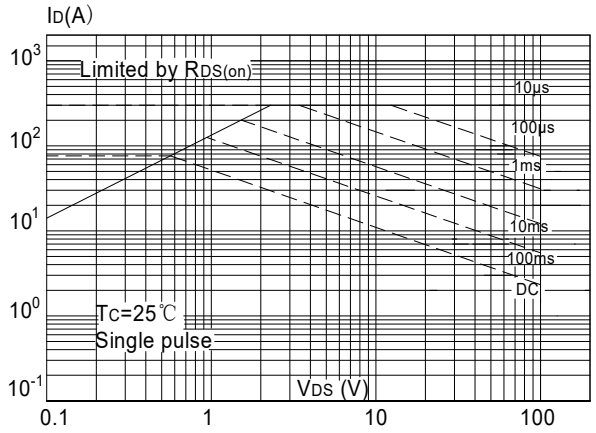


Figure 10: Maximum Continuous Drain Current vs. Case Temperature

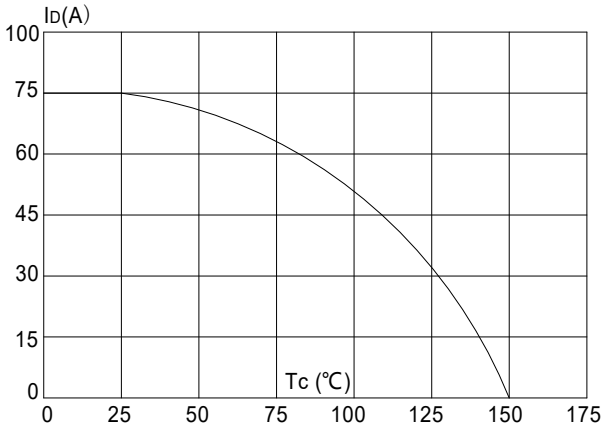
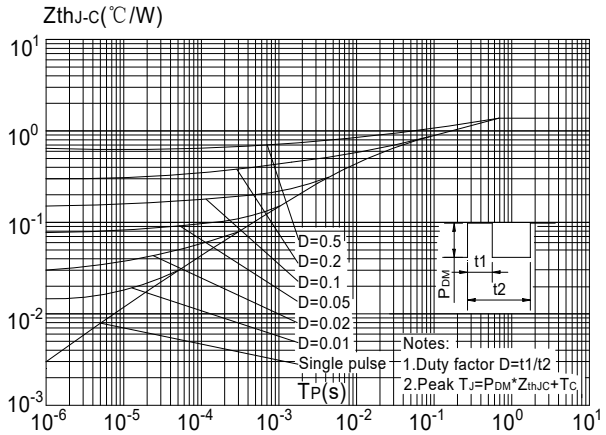


Figure.11: Maximum Effective Transient Thermal Impedance, Junction-to-Case



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Test Circuit

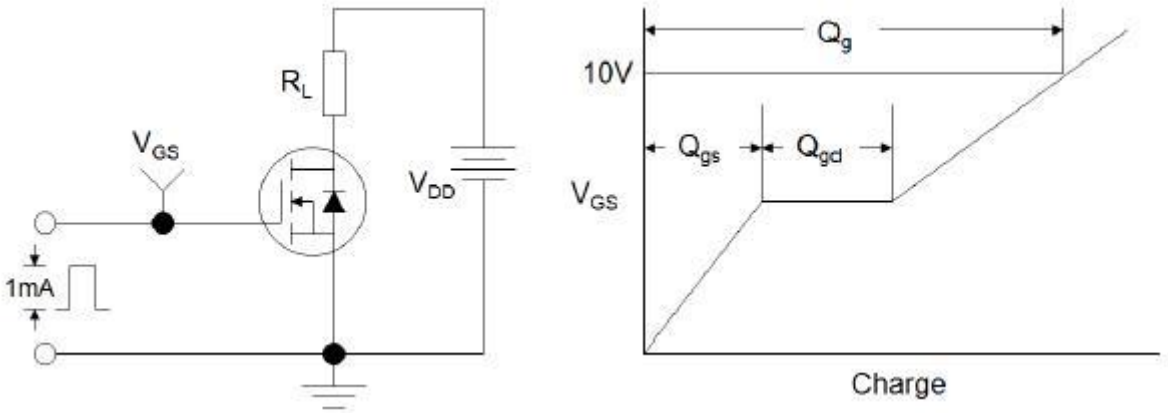

Figure1:Gate Charge Test Circuit & Waveform

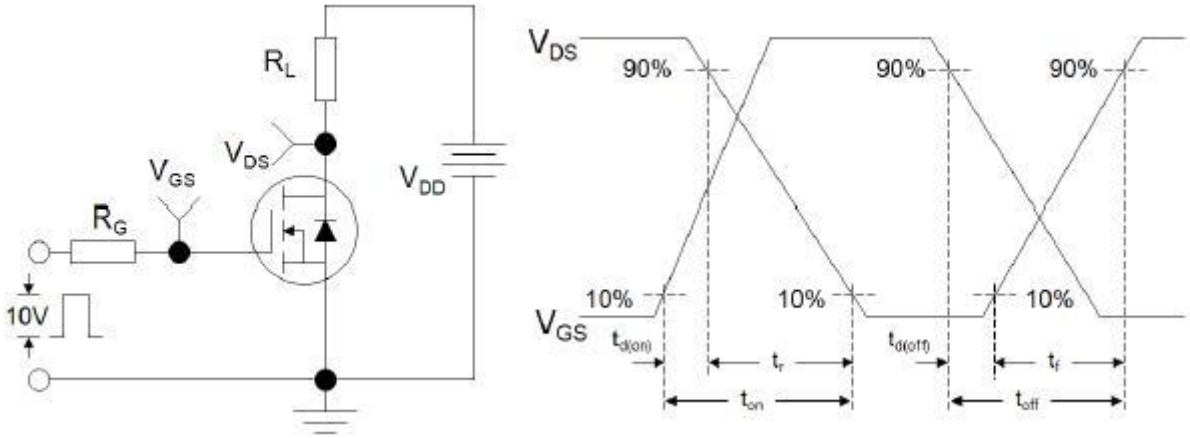

Figure 2: Resistive Switching Test Circuit & Waveforms

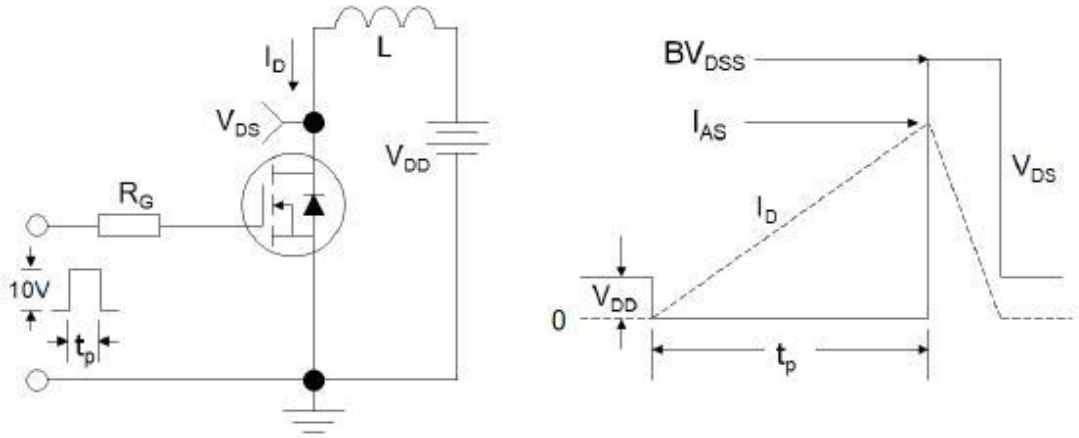

Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms

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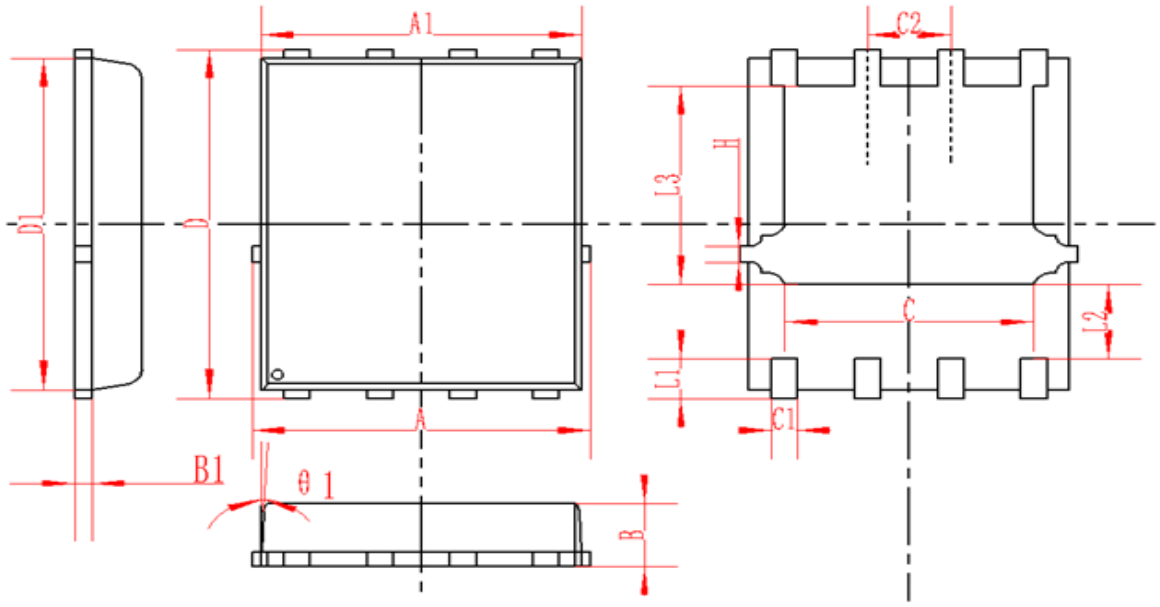
DFN5X6-8L Package Information



SYMBOL	MM			INCH		
	MIN	NOM	MAX	MIN	NOM	MAX
A	4.95	5	5.05	0.195	0.197	0.199
A1	4.82	4.9	4.98	0.190	0.193	0.196
D	5.98	6	6.02	0.235	0.236	0.237
D1	5.67	5.75	5.83	0.223	0.226	0.230
B	0.9	0.95	1	0.035	0.037	0.039
B1	0.254REF			0.010REF		
C	3.95	4	4.05	0.156	0.157	0.159
C1	0.35	0.4	0.45	0.014	0.016	0.018
C2	1.27TYP			0.5TYP		
θ1	8°	10°	12°	8°	10°	12°
L1	0.63	0.64	0.65	0.025	0.025	0.026
L2	1.2	1.3	1.4	0.047	0.051	0.055
L3	3.415	3.42	3.425	0.134	0.135	0.135
H	0.24	0.25	0.26	0.009	0.010	0.010

REEL SPECIFICATION

P/N	PKG	QTY
AON6226-MS	DFN5X6-8L	5000

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